dttis 2026

21st IEEE International conference on Design, Test & Technology of Integrated Systems

November 4 - 6, 2026, Hammamet, Tunisia

IEEE DTTIS’2026 Call For Special Sessions

Aim of the Special Sessions:

Special sessions target, but are not limited to, hot and emerging topics. Proposers of special sessions are assumed to be able and willing to serve as organizers of the session, i.e. contact speakers, moderators, etc. Special session organizers can also be speakers or moderators in their own proposals. Prospective organizers should submit a one or two-page abstract outlining the session’s scope and topic(s), the objectives and relevance of the proposed session to IEEE DTTIS, the format of the session, and a list of prospectives participants. For more information, please contact the Special Session Chair.

Papers are solicited in, but not limited to, the following topics:

Integrated Systems Design

- Analog, digital, mixed, and RF circuits design
- System-on-a-chip (SoC) & System of Chips (SoC), MPSoC, NoC, SIP, and NIP design
- Embedded/ multiprocessor systems
- Hardware design for AI
- AI accelerators
- MEMS, NEMS and MOEMS systems design
- Synthesis (physical, logic,...)
- Simulation, Validation & Verification
- Bio-engineering & Bio-chip design
- Electronics for energy harvesting
- Wireless communication systems design
- Opto-electronic System Design
- Biomedical Circuit & Systems
- Power electronics and systems design
- Sensory Systems Design
- Chiplet and disaggregation
- Intelligent and Autonomous Robotic Systems
- Embedded AI and TinyML
- Real-time inference under power, latency, and memory constraints
- Hardware–software co-design for intelligence at the edge
- Multi-agent coordination and distributed intelligence
- Heterogeneous computing platforms (CPU–GPU–FPGA–ASIC)
- Interoperability across hardware, software, and networks
- Hardware–software co-design for intelligence at the edge

Integrated Systems Testing

- Defect and Fault Modeling
- Analog, digital circuit test
- Mixed, and RF circuit testing
- MEMS/NEMS/MOEMS Testing
- 3D/2.5D Test
- Memory test
- Repair and diagnosis
- Reliability
- DFT, BIST and BISR
- Alternatives test strategies
- Fault Simulation, ATPG
- Yield Optimization
- Automotive reliability and test
- Reliability failures and modeling
- Electronic System Reliability
- Test and Security Issues
- ATE issues
- On-line Testing and fault Tolerance
- Delay testing

Integrated Systems Technology

- Process technologies
- Device modeling
- Material characterization
- Failure analysis
- Emerging technologies
- ICs Packaging
- Process technology
- Reliability issues
- 2.5 & 3D integration
- Circuit integrity

Special Issue

Analog Integrated Circuits and Signal Processing Journal

Special Session Chair:

- Prof. Ridha Djemal, ENIS, Tunisia
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Submission Deadline for Tutorial proposals: June, 30th 2026

Each Special Session proposal should describe concisely the content, importance and timeliness of the special session. It should contain the following sections:

- Special Session’s title.
- Summary describing the main focus and topics to be addressed and explained why the Special session is appropriate for DTTIS.
- The names and contact information of the organizers with a short biography.

Paper online submission: https://dttis2026.si2e.tn/